

Higgs BR study

ILC physics and software meeting

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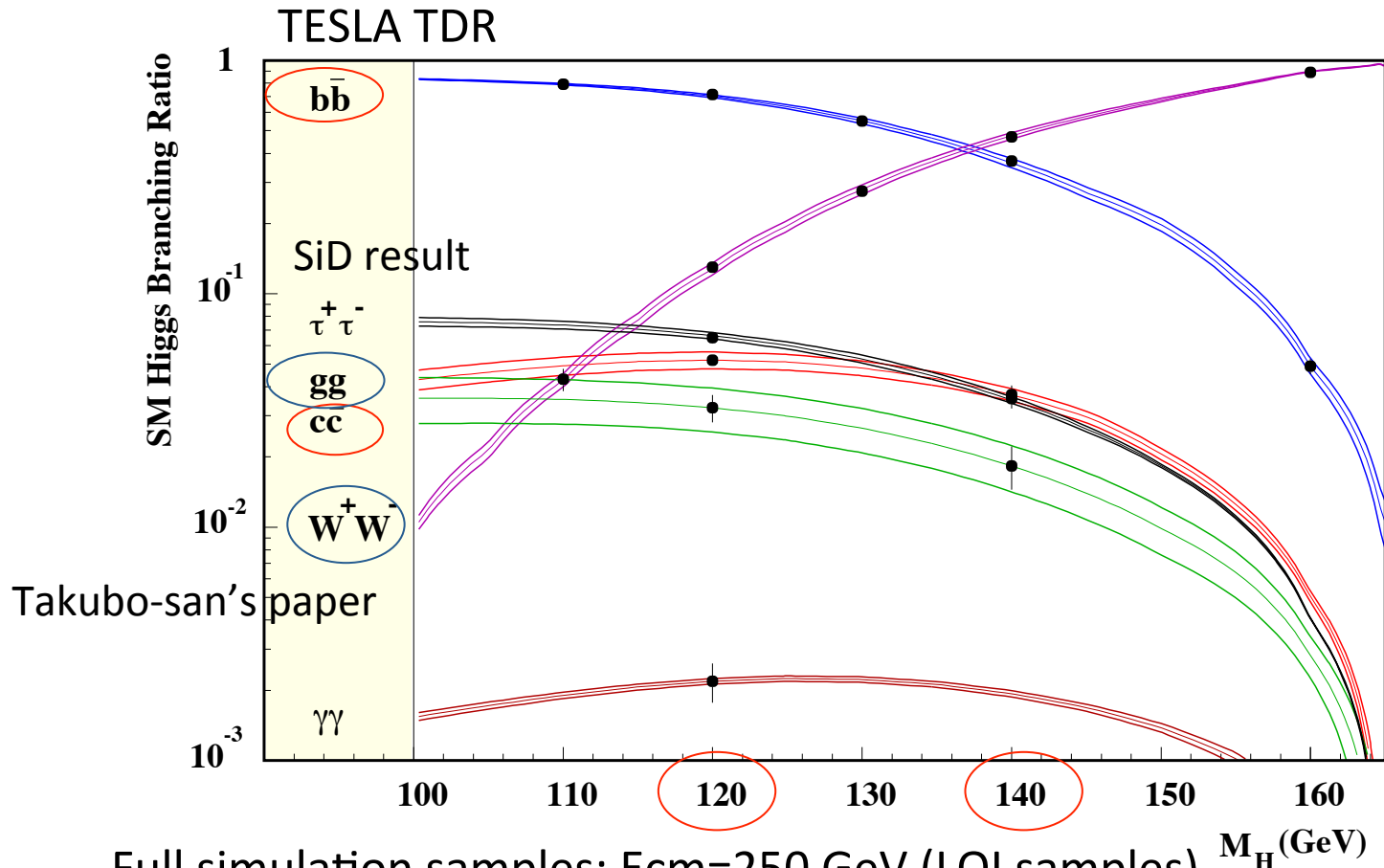
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Current status

- Template fitting stability test with different data sets of template and data
 - Fitted parameters are fluctuated by different statistics between the data and template
- qqH background reduction (qq background)
 - Large fluctuation from the limited statistics
- Different Higgs mass physics study
 - BR, recoil mass

Higgs BR with different mass

Aim: Update Higgs BR measurement accuracy plot after LOI



Full simulation samples: $E_{cm}=250$ GeV (LOI samples)

Signal : $M_H=120$ GeV, 130 and 140 GeV (Generated by Miyamoto-san)

Summary table of Higgs BR

Higgs mass	120 GeV		Mh=140 GeV	
Higgs decay	BR	$\Delta\text{BR}/\text{BR}$	BR	$\Delta\text{BR}/\text{BR}$
$H \rightarrow bb$	66.5%	2.1%, 4.8%	33.0%	
$H \rightarrow cc$	2.9%	6.7%, 8.4%	1.5%	
$H \rightarrow WW^*$	13.6%	15.7%	49.2%	
$H \rightarrow gg$	8.2%	12.2%	5.7%	
$H \rightarrow \tau\tau$	6.8%		3.5%	

My result is preliminarily

$H \rightarrow WW^*$ result is obtained from the Takubo-san's analysis

$H \rightarrow gg$ was studied at SiD (combined results of vvH and qqH by SiD)

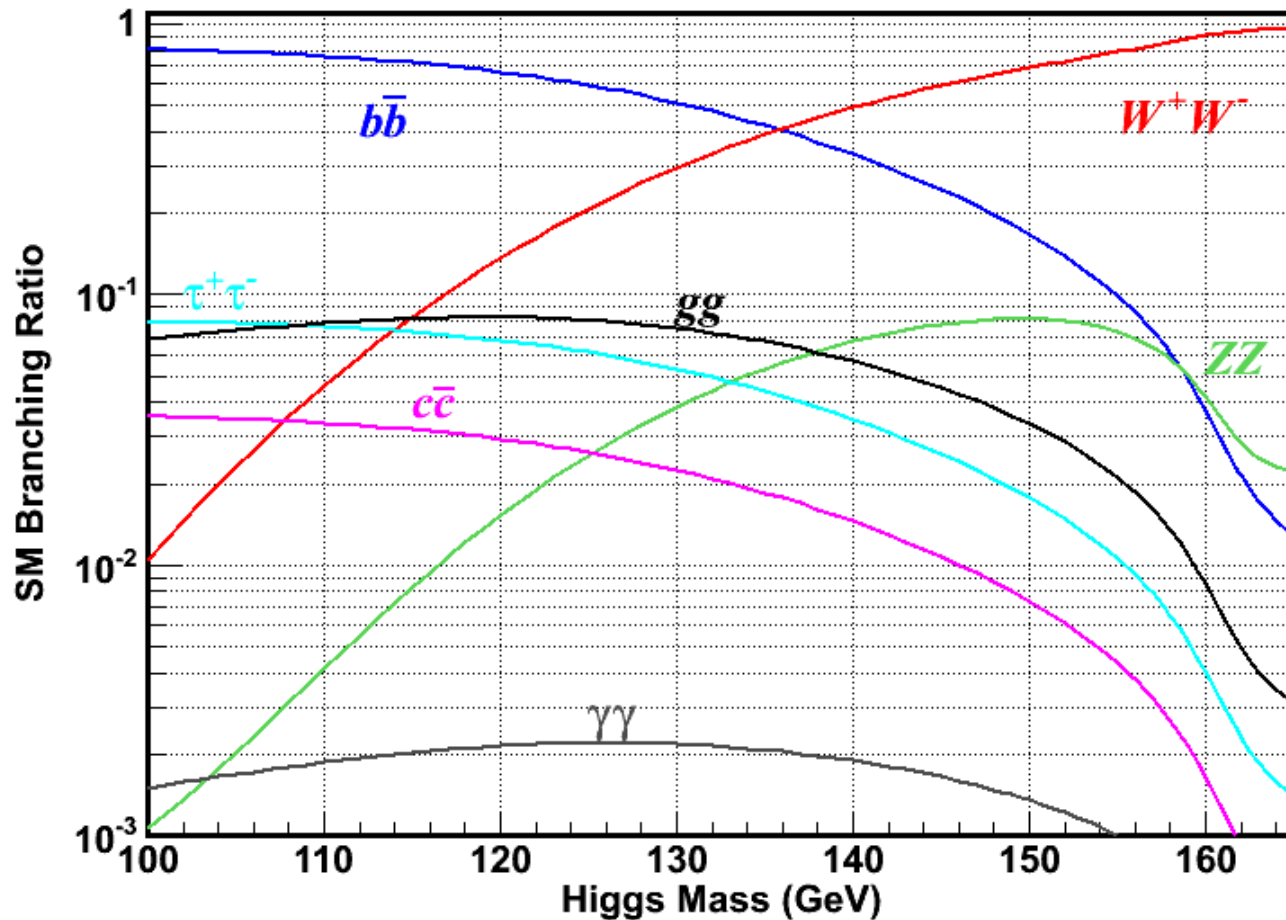
Each analysis include the σ_{ZH} accuracy of 2.5% from recoil mass study.

SiD include 4.7% uncertainty of σ_{ZH}

SiD ZH sutdy: Physical Review D 82, 03013 (2010)

$H \rightarrow WW^*$ anomalous coupling 1011.5805v2

Need to add the error bars on this plot generated by HDECAY



Fitted parameter r_{xx} definition

Current definition of fitted template sample rxx includes BR

$$N_{ijk}^{template} = \sum_{s=bb,cc,oth} r_s \left(\frac{N^{Hall}}{N^s} \right) \cdot N_{ijk}^s + r_{bkg} \cdot N_{ijk}^{bkg}$$

$$r_{oth} = 1 - r_{bb} - r_{cc} \quad r_{bkg} = 1 \text{ or free}$$

Possibility to reduce the fitting fluctuation fixed to $r_{bkg} = 1$, which assume the SM backgrounds are well understand in the template samples

Definition of fitted r_{xx}

$$r_{xx} = \epsilon_{xx} / \epsilon_{all} * BR(xx)$$

Extract absolute BR from the fitted parameter r_{xx} and ϵ_{xx} (cut efficiency)